FAIRCHILD SEMICONDUCTOR TM		

Unit Loading/Fan Out

Pin Names	December 1	U.L.	Input I _{IH} /I _{IL}		
	Description	HIGH/LOW	Output I _{OH} /I _{OL}		
D ₀ –D ₇	Data Inputs	1.0/1.0	20 μA/–0.6 mA		
CP	Clock Pulse Input (Active Rising Edge)	1.0/1.0	20 μA/–0.6 mA		
ŌĒ	3-STATE Output Enable Input (Active LOW)	1.0/1.0	20 μA/–0.6 mA		
O ₀ -O ₇	3-STATE Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)		

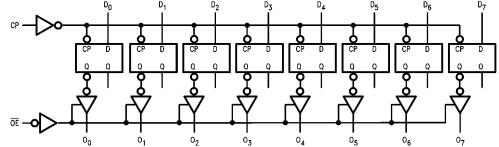
Functional Description

The 74F374 consists of eight edge-triggered flip-flops with individual D-type inputs and 3-STATE true outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D inputs that meet the setup and hold time requirements on the LOW-to-HIGH Clock (CP) transition. With the Output Enable (OE) LOW, the contents of the eight flip-flops are available at the outputs. When the $\overline{\text{OE}}$ is HIGH, the outputs go to the high impedance state. Operation of the OE input does not affected the state of the flipflops.

Truth Table

	Inputs		Internal	Output		
D _n	СР	OE	Register	O _n		
Н	~	L	Н	Н		
L	~	L	L	L		
X	X	Н	Х	Z		

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

H = HIGH Voltage Level L = LOW Voltage Level

X = Immaterial

Z = High Impedance $\[\] = LOW-to-HIGH Clock Transition \]$

Absolute Maximum Ratings(Note 1)

Recommended Operating Conditions

 $\begin{array}{ll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \end{array}$

 $\begin{array}{lll} \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{V}_{\mbox{CC}} \mbox{ Pin Potential to Ground Pin} & -0.5\mbox{V to } +7.0\mbox{V} \\ \mbox{Input Voltage (Note 2)} & -0.5\mbox{V to } +7.0\mbox{V} \\ \end{array}$

Input Current (Note 2) —30 mA to +5.0 mA

Voltage Applied to Output in HIGH State (with V_{CC} = 0V)

 $\begin{array}{ll} \mbox{Standard Output} & -0.5\mbox{V to V}_{\mbox{CC}} \\ \mbox{3-STATE Output} & -0.5\mbox{V to } +5.5\mbox{V} \end{array}$

Current Applied to Output

% in LOW State (Max) twice the rated I_{OL} (mA) ESD Last Passing Voltage (Min) 4000V

Free Air Ambient Temperature 0° C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

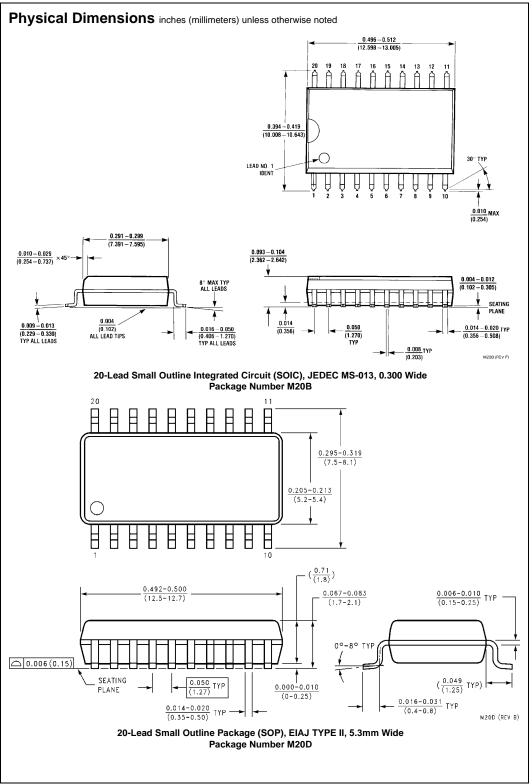
Symbol	Parameter		Min	Тур	Max	Units	v _{cc}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	$I_{IN} = -18 \text{ mA}$
V _{OH}	Output HIGH	10% V _{CC}	2.5					I _{OH} = -1 mA
	Voltage	10% V _{CC}	2.4			V	Min	$I_{OH} = -3 \text{ mA}$
		5% V _{CC}	2.7			V	IVIII	$I_{OH} = -1 \text{ mA}$
		5% V _{CC}	2.7					$I_{OH} = -3 \text{ mA}$
V _{OL}	Output LOW	10% V _{CC}			0.5	V	Min	I _{OL} = 24 mA
	Voltage							
I _{IH}	Input HIGH				5.0		Max	V _{IN} = 2.7V
	Current				5.0	μА	iviax	$v_{IN} = 2.7 v$
I _{BVI}	Input HIGH Current				7.0			., 7.0)/
	Breakdown Test				7.0	μΑ	Max	V _{IN} = 7.0V
I _{CEX}	Output HIGH				50		Max	V V
	Leakage Current				30	μА	IVIAX	$V_{OUT} = V_{CC}$
V _{ID}	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A}$
	Test		4.75			V	0.0	All Other Pins Grounded
I _{OD}	Output Leakage				3.75		0.0	V _{IOD} = 150 mV
	Circuit Current				3.75	μА	0.0	All Other Pins Grounded
I _{IL}	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$
l _{OZH}	Output Leakage Current				50	μΑ	Max	V _{OUT} = 2.7V
l _{OZL}	Output Leakage Current				-50	μΑ	Max	V _{OUT} = 0.5V
los	Output Short-Circuit Current		-60		-150	mA	Max	V _{OUT} = 0V
I _{ZZ}	Bus Drainage Test				500	μΑ	0.0V	V _{OUT} = 5.25V
I _{CCZ}	Power Supply Current			55	86	mA	Max	$V_O = HIGH Z$

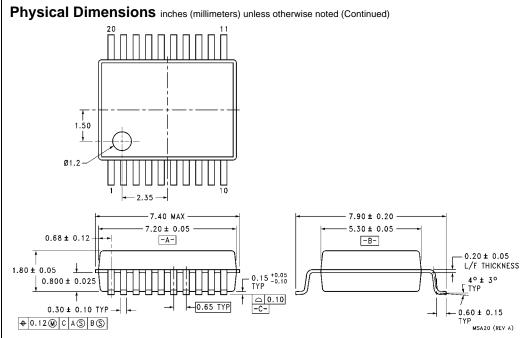
AC Electrical Characteristics

Symbol	Parameter	$T_A = +25^{\circ}$ C $V_{CC} = +5.0$ V $C_L = 50$ pF		V _{CC} =	c to +125°C - +5.0V 50 pF	$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50$ pF		Units	
		Min	Тур	Max	Min	Max	Min	Max	
f _{MAX}	Maximum Clock Frequency	100	140		60		70		MHz
t _{PLH}	Propagation Delay	4.0	6.5	8.5	4.0	10.5	4.0	10.0	
t_{PHL}	CP to O _n	4.0	6.5	8.5	4.0	11.0	4.0	10.0	ns
t _{PZH}	Output Enable Time	2.0	9.0	11.5	2.0	14.0	2.0	12.5	
t_{PZL}		2.0	5.8	7.5	2.0	10.0	2.0	8.5	
t _{PHZ}	Output Disable Time	2.0	5.3	7.0	2.0	8.0	2.0	8.0	ns
t_{PLZ}		1.5	4.3	5.5	1.5	7.5	1.5	6.5	

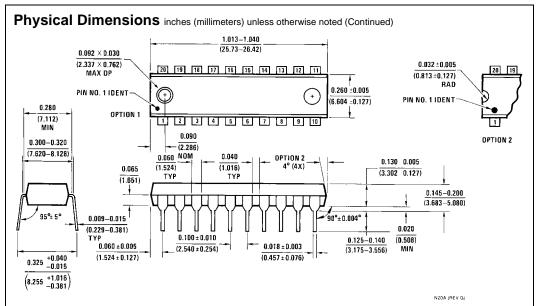
AC Operating Requirements

Symbol	Parameter	$T_A = +25$ °C $V_{CC} = +5.0V$		$T_A = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$		Units
		Min	Max	Min	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	2.0		2.5		2.0		
t _S (L)	D _n to CP	2.0		2.0		2.0		20
t _H (H)	Hold Time, HIGH or LOW	2.0		2.0		2.0		ns
t _H (L)	D _n to CP	2.0		2.5		2.0		
t _W (H)	CP Pulse Width	7.0		7.0		7.0		no
$t_W(L)$	HIGH or LOW	6.0		6.0		6.0		ns





20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide Package Number MSA20



20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N20A

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